

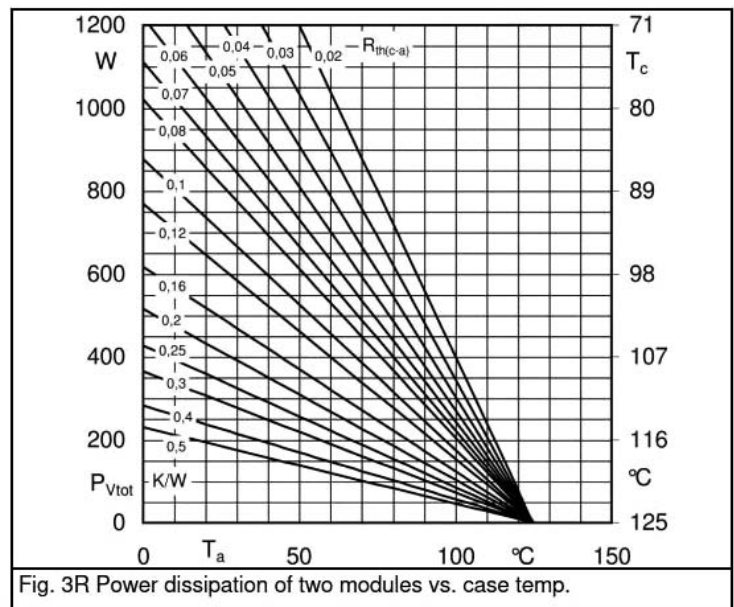
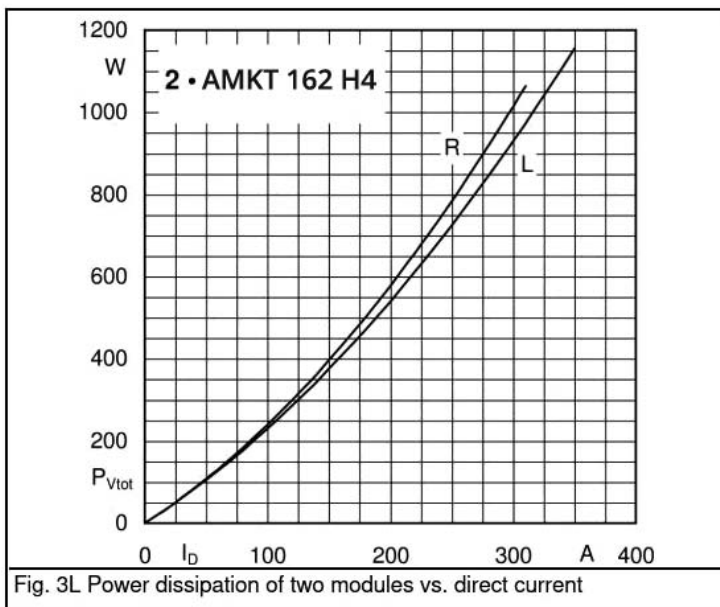
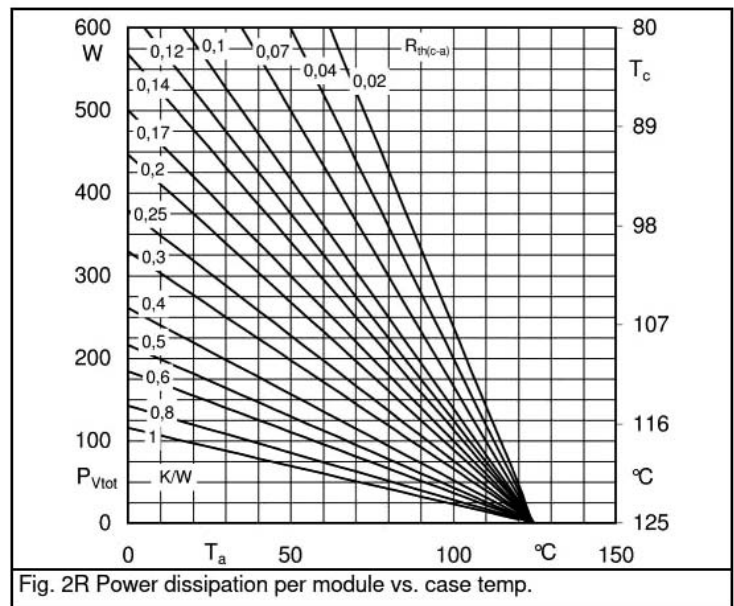
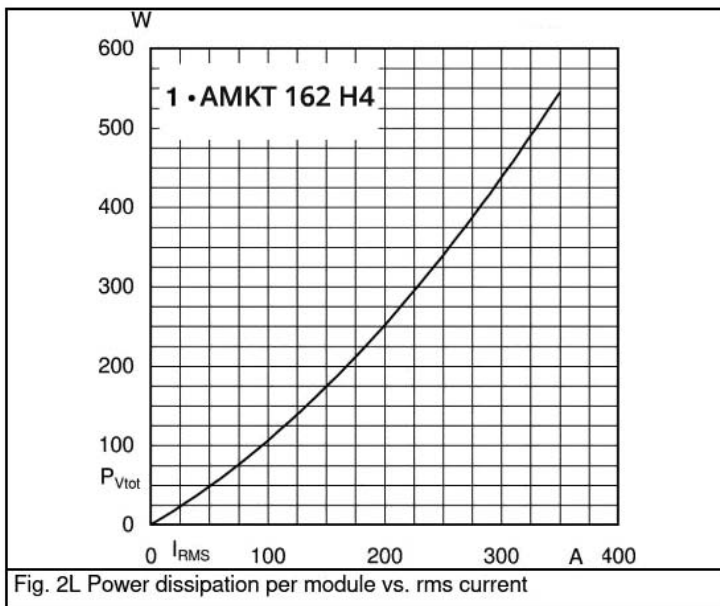
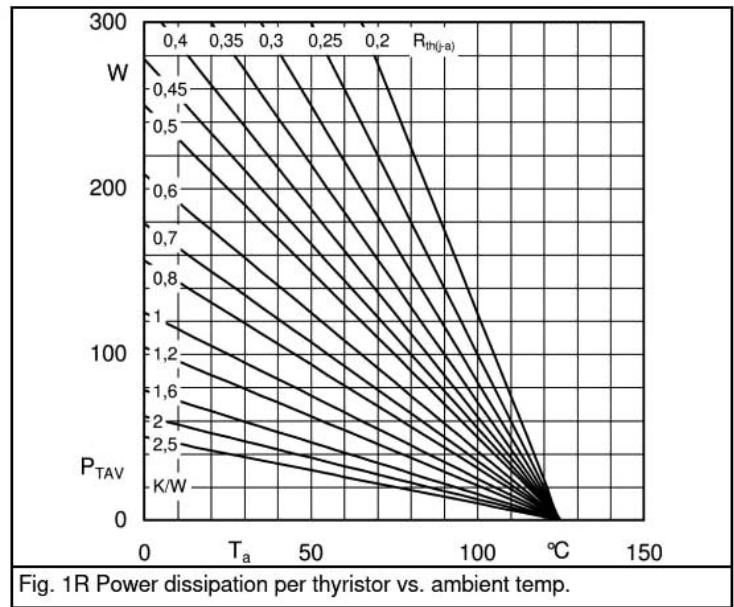
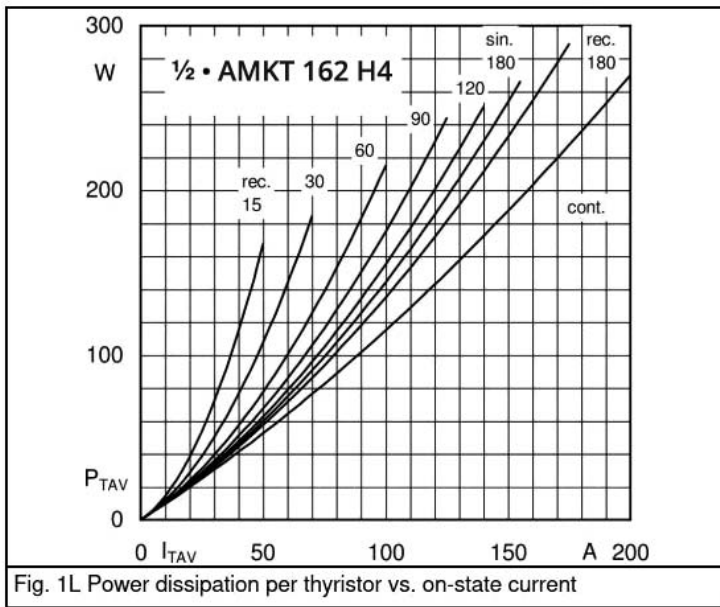
# Thyristor Modules

## AMKT 162 H4



$V_{RSM}$ V	$V_{RRM}, V_{DRM}$ V	$I_{TRMS} = 250$ A (maximum value for continuous operation) $I_{TAV} = 162$ A (sin 180; $T_c = 77$ °C)	
2100 2300	2000 2200	AMKT 162-20E H4 AMKT 162-22E H4	

Symbols and parameters			Values	Units
$I_{TAV}$	Average on-state current	sin. 180; $T_c = 85$ (100)°C	143 (101)	A
$I_{TSM}$	Surge on-state current	$T_{vj} = 25$ °C; 10 ms	5200	A
		$T_{vj} = 125$ °C; 10 ms	4800	A
$I^2t$	$I^2t$ value, rating for fusing	$T_{vj} = 25$ °C; 10 ms	135000	A <sup>2</sup> s
		$T_{vj} = 125$ °C; 10 ms	115000	A <sup>2</sup> s
$V_T$	On-state voltage	$T_{vj} = 25$ °C; $I_T = 500$ A	max. 1.65	V
$V_{T(TO)}$	On-state threshold voltage	$T_{vj} = 125$ °C	max. 0.95	V
$r_T$	On-state slope resistance	$T_{vj} = 125$ °C	max. 2	mΩ
$I_{DD}; I_{RD}$	Forward off-state current; Direct reverse current	$T_{vj} = 125$ °C, $V_{RD} = V_{RRM}$ ; $V_{DD} = V_{DRM}$	max. 60	mA
$t_{gd}$	Gate controlled turn-on delay time	$T_{vj} = 25$ °C; $I_G = 1$ A; $di_G/dt = 1$ A/μs	1	μs
$t_{gr}$	Gate controlled rise time	$V_D = 0.67 * V_{DRM}$	2	μs
$(di/dt)_{cr}$	Critical rate of rise of on-state current	$T_{vj} = 125$ °C	max. 200	A/μs
$(dv/dt)_{cr}$	Critical rate of rise of off-state voltage	$T_{vj} = 125$ °C	max. 1000	V/μs
$t_q$	Turn-off time	$T_{vj} = 125$ °C	50...150	μs
$I_H$	Holding current	$T_{vj} = 25$ °C; typ. / max	150 / 400	mA
$I_L$	Latching current	$T_{vj} = 25$ °C; $R_G = 33$ Ω; typ. / max	300 / 1000	mA
$V_{GT}$	Gate trigger voltage	$T_{vj} = 25$ °C; d.c.	min. 2	V
$I_{GT}$	Gate trigger current	$T_{vj} = 25$ °C; d.c.	min. 150	mA
$V_{GD}$	Gate non-trigger voltage	$T_{vj} = 125$ °C; d.c.	max. 0.25	V
$I_{GD}$	Gate non-trigger current	$T_{vj} = 125$ °C; d.c.	max. 10	mA
$R_{th(j-c)}$	Thermal resistance, junction to case	cont. DC; per chip / per module	0.16 / 0.08	K/W
		sin.180; per chip / per module	0.17 / 0.085	K/W
		rec.120; per chip / per module	0.19 / 0.095	K/W
$R_{th(c-s)}$	Thermal resistance, junction to heatsink	per chip / per module	0.1 / 0.05	K/W
$T_{vj}$	Virtual junction temperature		-40 ... +125	°C
$T_{stg}$	Storage temperature range		-40 ... +125	°C
$V_{ISOL}$	Insulation test voltage (r.m.s.)	a.c. 50 Hz; r.m.s.; 1s / 1min.	4800 / 4000	V~
$M_s$	Mounting torque on heatsink	min / max	5 ± 15 %	Nm
$M_t$	Mounting torque for terminals	min / max	5 ± 15 %	Nm
$a$	Maximum allowable acceleration		5*9.81	m/s <sup>2</sup>
$W$	Weight	approx.	175	g



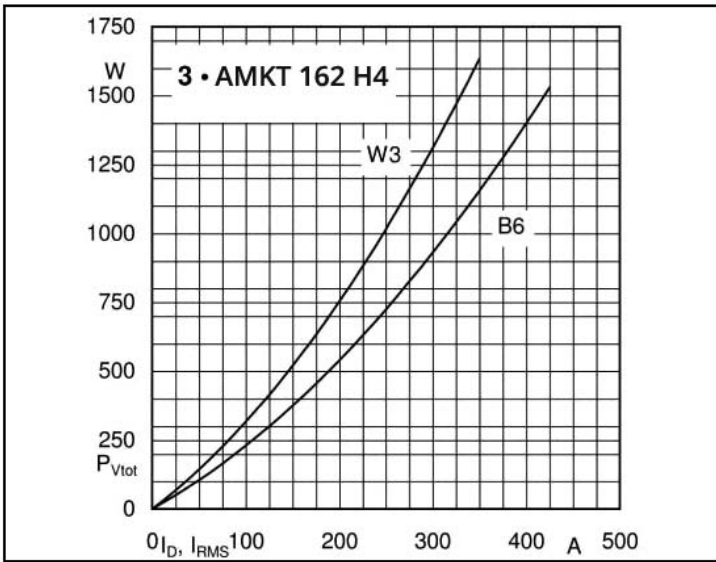


Fig. 4L Power dissipation of three modules vs. direct and rms current

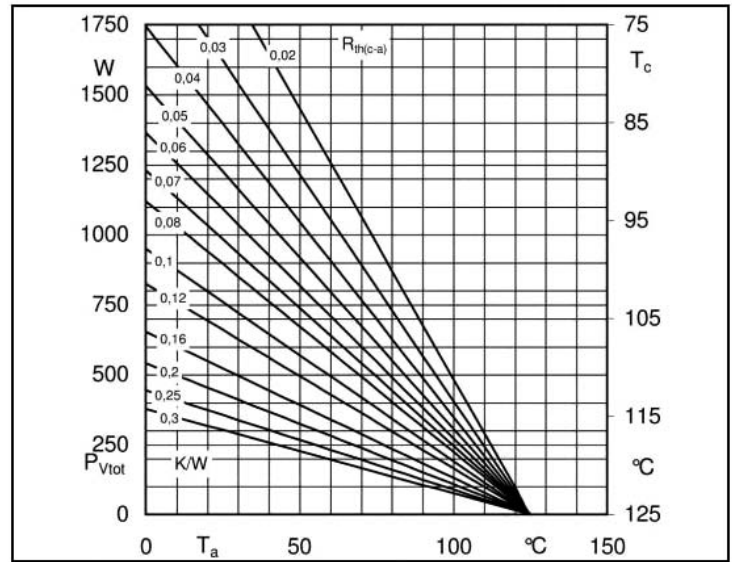


Fig. 4R Power dissipation of three modules vs. case temp.

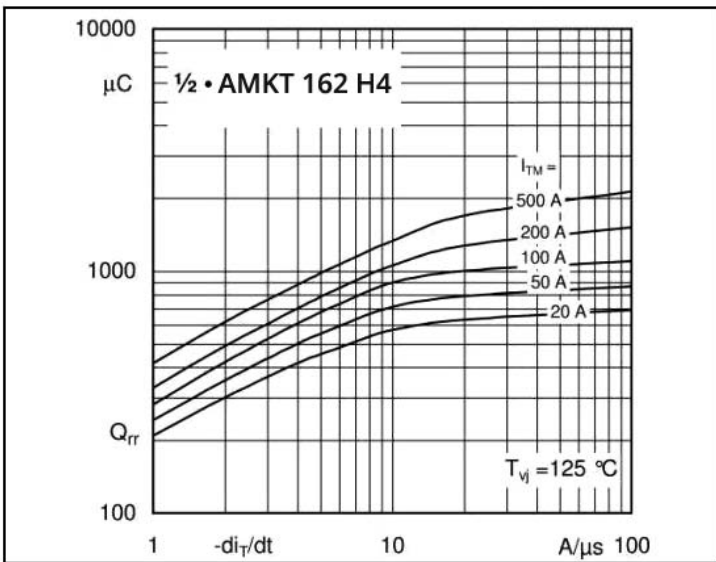


Fig. 5 Recovered charge vs. current decrease

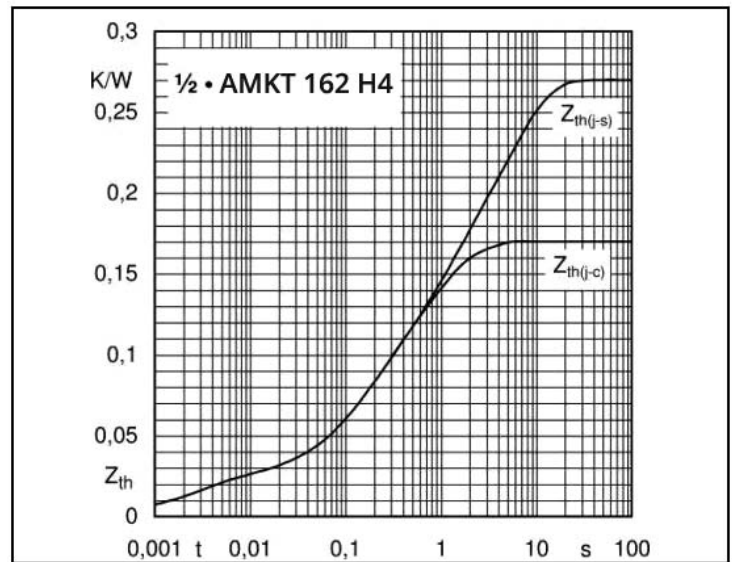


Fig. 6 Transient thermal impedance vs. time

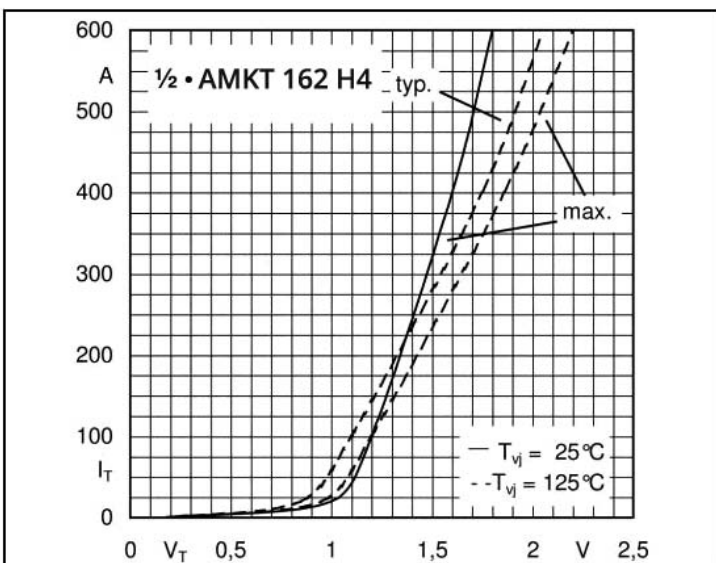


Fig. 7 On-state characteristics

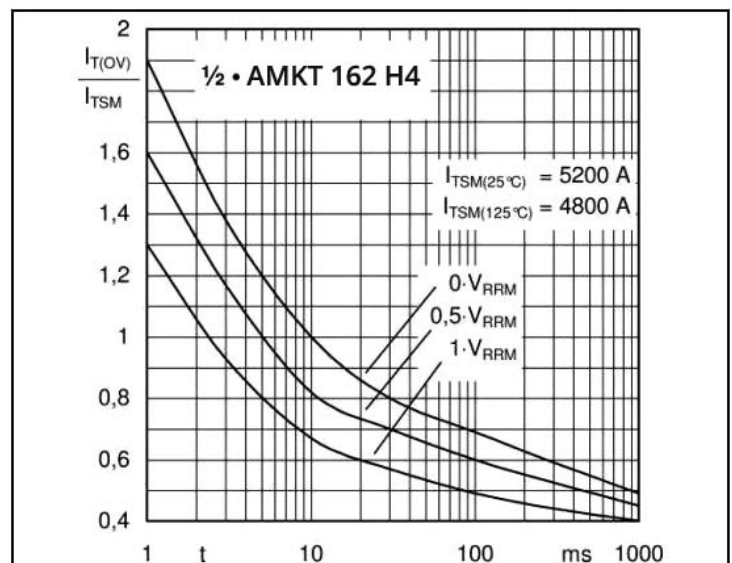
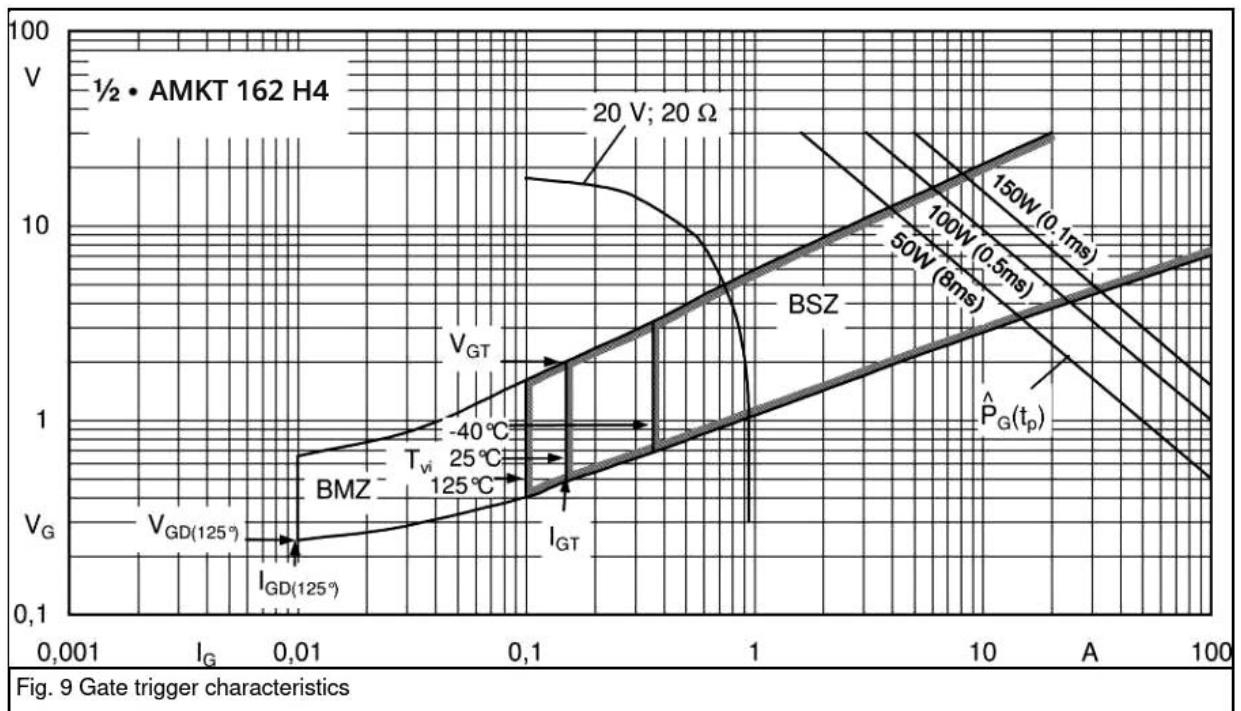
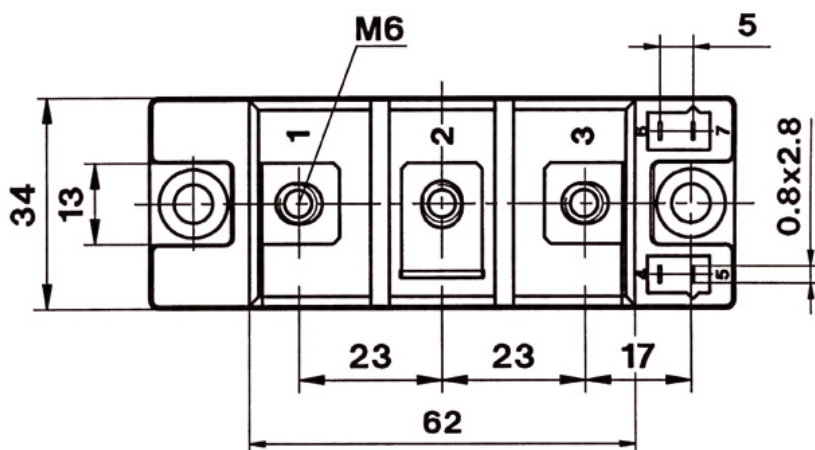
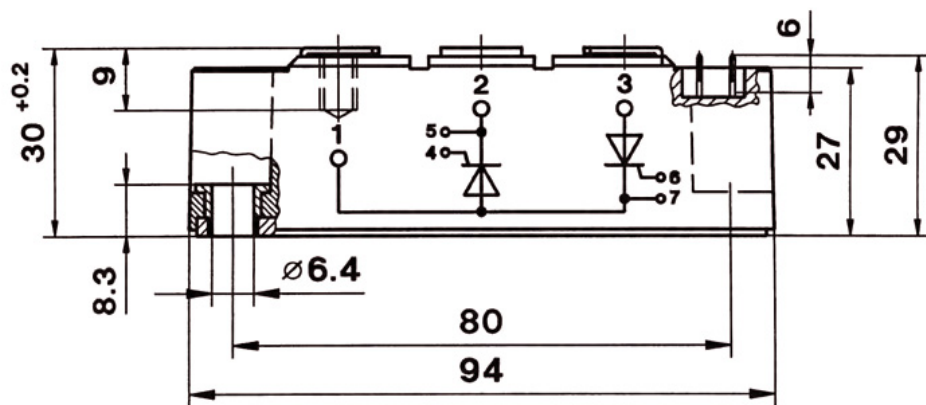


Fig. 8 Surge overload current vs. time



### DIMENSIONS



Dimensions in mm

### TOPOLOGY OF INTERNAL CONNECTION

